



## UF25N20

Preliminary

Power MOSFET

### 25A, 200V N-CHANNEL POWER MOSFET

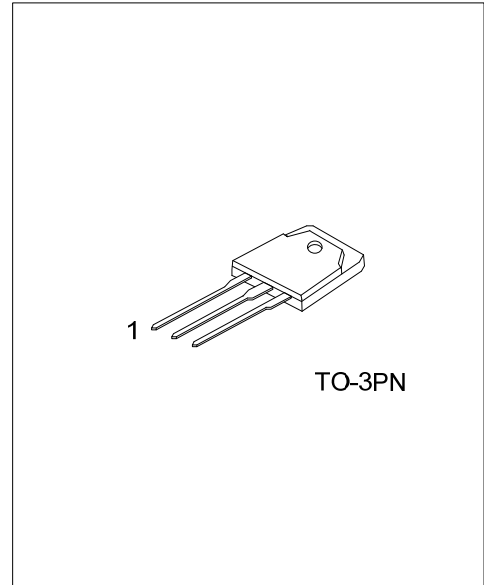
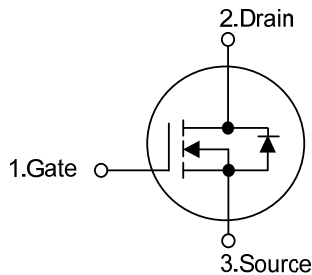
#### DESCRIPTION

The UTC **UF25N20** is a N-channel enhancement MOSFET using UTC's advanced technology to provide the customers with perfect  $R_{DS(ON)}$ , high switching speed, high current capacity and low gate charge.

#### FEATURES

- \*  $R_{DS(ON)} \leq 0.135 \Omega$  @  $V_{GS}=10V$ ,  $I_D=12.5A$
- \* High switching speed
- \* 100% avalanche tested
- \* Exceptional dv/dt capability

#### SYMBOL



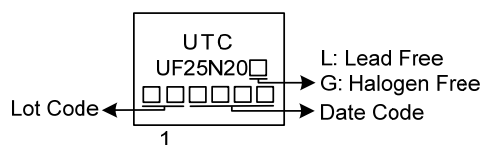
#### ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
UF25N20L-T3N-T	UF25N20G-T3N-T	TO-3PN	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>UF25N20G-T3N-T</p> <p>(1)Packing Type</p> <p>(2)Package Type</p> <p>(3)Green Package</p>	<p>(1) T: Tube</p> <p>(2) T3N: TO-3PN</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
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#### MARKING



■ ABSOLUTE MAXIMUM RATINGS ( $T_C=25^{\circ}\text{C}$ , unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		$V_{DSS}$	200	V
Gate-Source Voltage		$V_{GSS}$	$\pm 30$	V
Continuous Drain Current	Continuous	$I_D$	25	A
	Pulsed	$I_{DM}$	50	A
Single Pulsed Avalanche Energy		$E_{AS}$	673	mJ
Peak Diode Recovery $dv/dt$ (Note 4)		$dv/dt$	4.3	V/ns
Power Dissipation		$P_D$	160	W
Junction Temperature		$T_J$	+150	$^{\circ}\text{C}$
Storage Temperature		$T_{STG}$	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3.  $L = 30\text{mH}$ ,  $I_{AS} = 6.7\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^{\circ}\text{C}$

4.  $I_{SD} \leq 25\text{A}$ ,  $di/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^{\circ}\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	$\theta_{JA}$	40	$^{\circ}\text{C}/\text{W}$
Junction to Case	$\theta_{JC}$	0.78	$^{\circ}\text{C}/\text{W}$

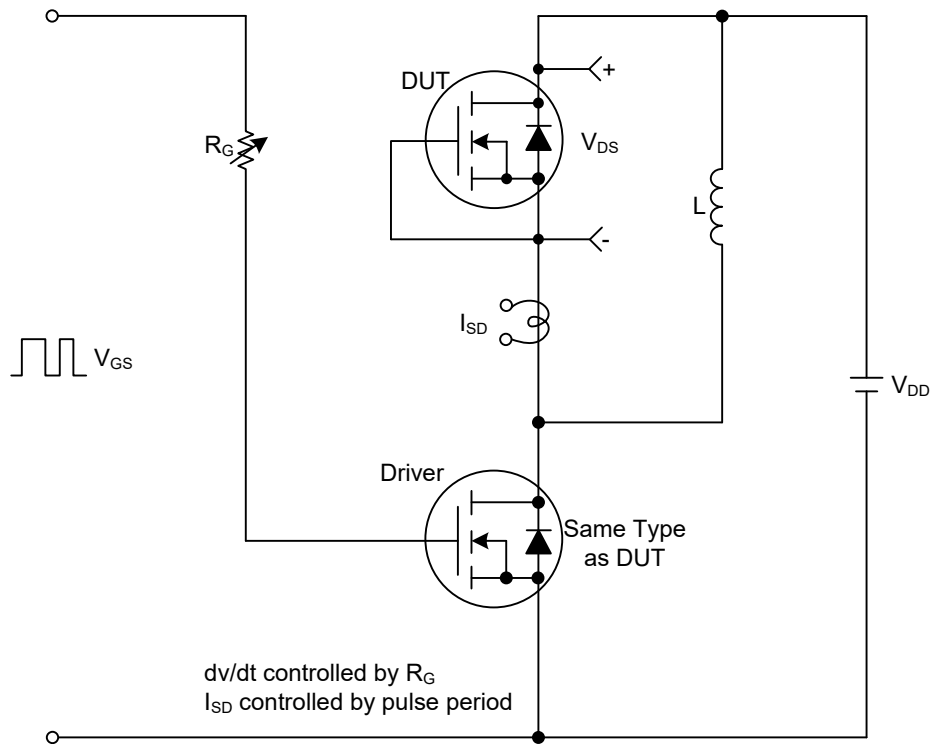
■ ELECTRICAL CHARACTERISTICS ( $T_C=25^{\circ}\text{C}$ , unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	200			V
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> =200V, V <sub>GS</sub> =0V			10	μA
Gate-Source Leakage Current	Forward	I <sub>GSS</sub>	V <sub>GS</sub> =+30V, V <sub>DS</sub> =0V			+100	nA
	Reverse		V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		V <sub>GS(TH)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2.0		4.0	V
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =12.5A			0.135	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C <sub>ISS</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz		1035		pF
Output Capacitance		C <sub>OSS</sub>			175		pF
Reverse Transfer Capacitance		C <sub>RSS</sub>			10.7		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q <sub>G</sub>	V <sub>DS</sub> =160V, V <sub>GS</sub> =10V, I <sub>D</sub> =25A (Note 1, 2)		28		nC
Gate to Source Charge		Q <sub>GS</sub>			11		nC
Gate to Drain Charge		Q <sub>GD</sub>			7.5		nC
Turn-ON Delay Time		t <sub>D(ON)</sub>	V <sub>DD</sub> =100V, V <sub>GS</sub> =10V, I <sub>D</sub> =25A, R <sub>G</sub> =25Ω (Note 1, 2)		10		ns
Rise Time		t <sub>R</sub>			18.4		ns
Turn-OFF Delay Time		t <sub>D(OFF)</sub>			40		ns
Fall-Time		t <sub>F</sub>			22		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I <sub>S</sub>				25	A
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>				50	A
Drain-Source Diode Forward Voltage		V <sub>SD</sub>	I <sub>S</sub> =25A, V <sub>GS</sub> =0V			1.11	V
Body Diode Reverse Recovery Time		t <sub>rr</sub>	I <sub>S</sub> =25A, V <sub>GS</sub> =0V, dI <sub>F</sub> /dt=100A/μs		136		ns
Reverse Recovery Charge		Q <sub>rr</sub>	(Note 1)		0.58		μC

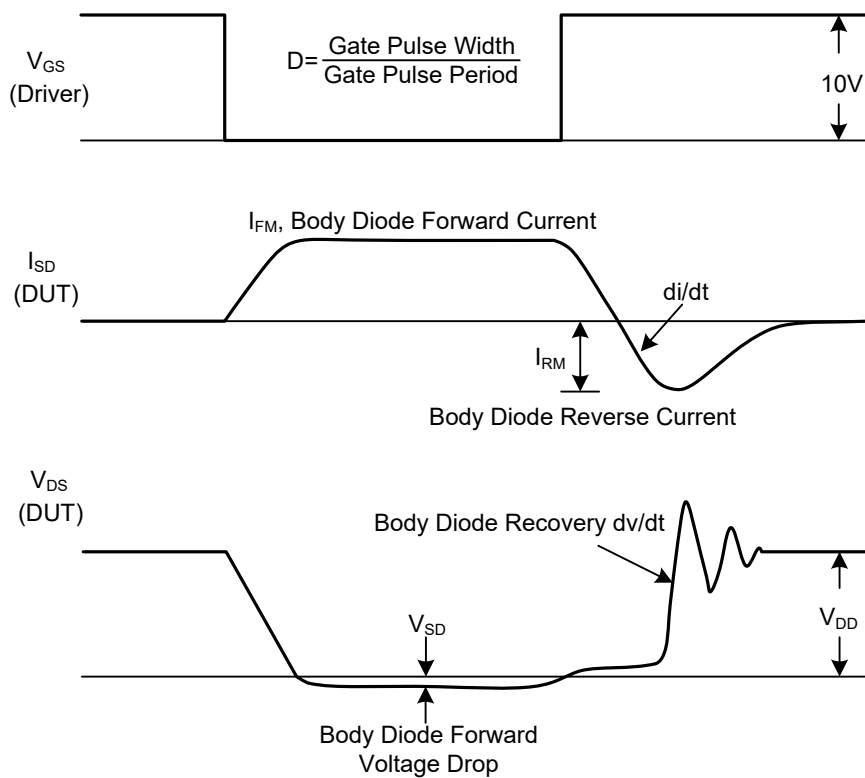
Notes: 1. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$ .

2. Essentially independent of operating temperature.

# ■ TEST CIRCUITS AND WAVEFORMS

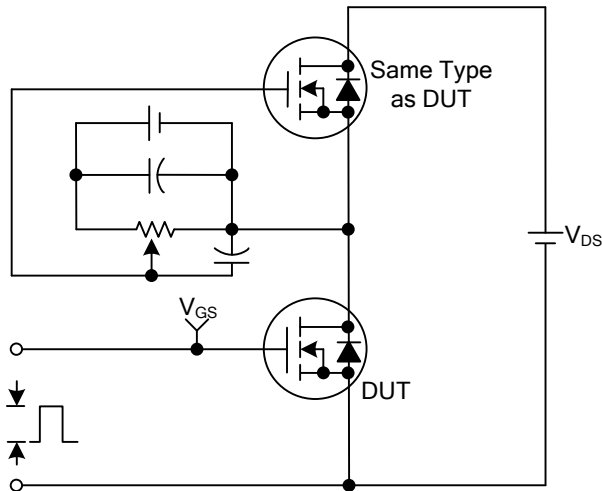


**Peak Diode Recovery dv/dt Test Circuit**

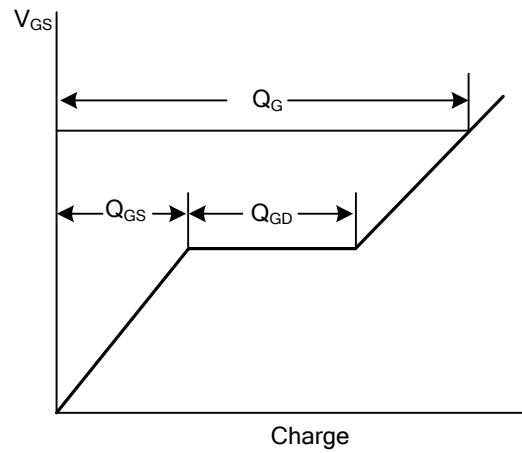


**Peak Diode Recovery dv/dt Waveforms**

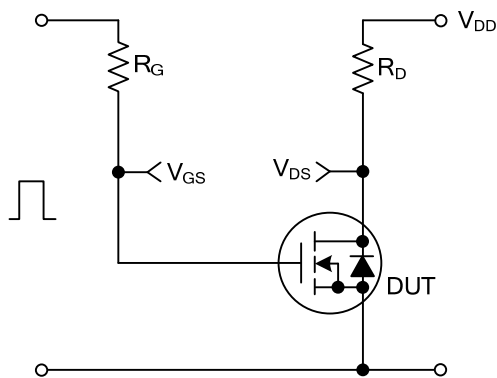
### ■ TEST CIRCUITS AND WAVEFORMS



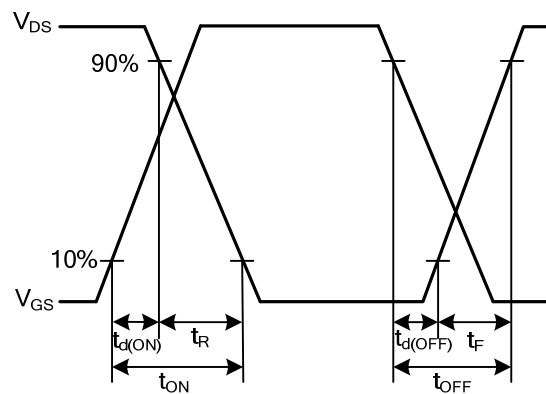
Gate Charge Test Circuit



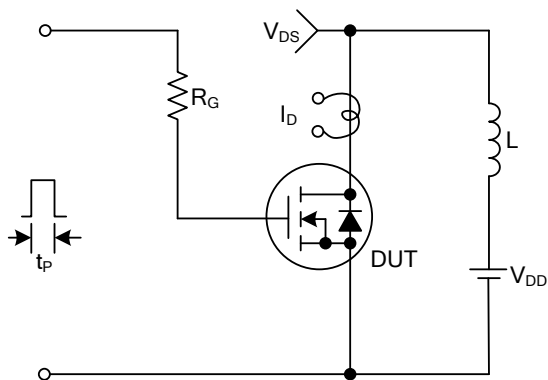
Gate Charge Waveforms



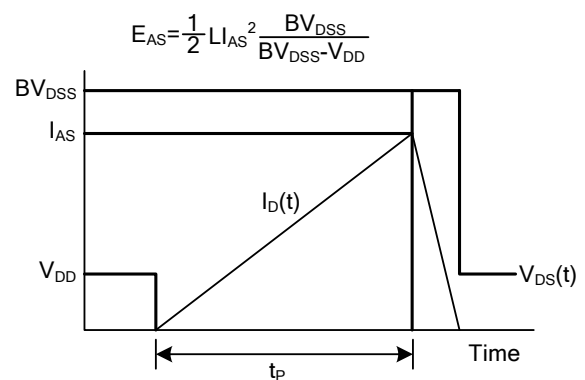
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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